

10/521563

DT09 Rec'd PCT/PTO 1 9 JAN 2005

PATENT
ATTORNEY DOCKET NO. 0075/021001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Detlef KNEBEL et al. Art Unit:
Application No.: filed concurrently Examiner:
Title: METHOD FOR LOCALLY HIGHLY RESOLVED, MASS-SPECTROSCOPIC
CHARACTERIZATION OF SURFACES USING SCANNING PROBE
TECHNOLOGY

International Application No.: PCT/DE2003/002493
International Filing Date : July 24, 2003
Priority Date : July 24, 2002
U.S. Filing Date : January 19, 2005

Mail Stop PCT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

PRELIMINARY AMENDMENT

Sir:

Prior to the examination and calculation of the filing fee
for this application, please amend the application as follows:

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 6 of this paper.